TOSHIBA Field Effect Transistor Silicon N Channel MOS Type ( $L^2-\pi$ -MOSV)

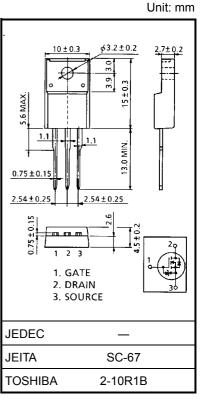
# 2SK2312

Chopper Regulator, DC–DC Converter and Motor Drive Applications

- 4 V gate drive
- Low drain-source ON resistance  $: R_{DS} (ON) = 13 \text{ m}\Omega (typ.)$
- High forward transfer admittance  $|Y_{fs}| = 40 \text{ S (typ.)}$
- Low leakage current  $: I_{DSS} = 100 \ \mu A \ (max) \ (V_{DS} = 60 \ V)$
- Enhancement-mode :  $V_{th} = 0.8 \sim 2.0 V (V_{DS} = 10 V, I_D = 1 mA)$

#### Maximum Ratings (Ta = 25°C)

Characteri	stics	Symbol	Rating	Unit	
Drain-source voltage		V <sub>DSS</sub>	60	V	
Drain-gate voltage (R <sub>GS</sub> = 20 kΩ)		V <sub>DGR</sub>	60	V	
Gate-source voltage		V <sub>GSS</sub>	±20	V	
Drain current	DC (Note 1)	۱ <sub>D</sub>	45	А	
	Pulse (Note 1)	I <sub>DP</sub>	180	А	
Drain power dissipatio	n (Tc = 25°C)	PD	45	W	
Single pulse avalanche energy (Note 2)		E <sub>AS</sub>	701	mJ	
Avalanche current		I <sub>AR</sub>	45	А	
Repetitive avalanche energy (Note 3)		E <sub>AR</sub>	4.5	mJ	
Channel temperature		T <sub>ch</sub>	150	°C	
Storage temperature range		T <sub>stg</sub>	-55~150	°C	



Weight: 1.9 g (typ.)

#### **Thermal Characteristics**

Characteristics	Symbol	Max	Unit
Thermal resistance, channel to case	R <sub>th (ch-c)</sub>	2.78	°C / W
Thermal resistance, channel to ambient	R <sub>th (ch−a)</sub>	62.5	°C / W

Note 1: Please use devices on condition that the channel temperature is below 150°C. Note 2:  $V_{DD} = 25 \text{ V}$ ,  $T_{ch} = 25^{\circ}\text{C}$  (initial),  $L = 471 \text{ }\mu\text{H}$ ,  $R_G = 25 \Omega$ ,  $I_{AR} = 45 \text{ A}$ 

Note 3: Repetitive rating; Pulse width limited by maximum channel temperature.

This transistor is an electrostatic sensitive device. Please handle with caution.

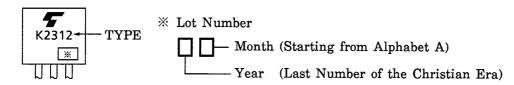
Electrical Characteristics (Ta = 25°C)

Charae	cteristics	Symbol	Test Condition	Min	Тур.	Max	Unit
Gate leakage cu	urrent	I <sub>GSS</sub>	$V_{GS}$ = ±16 V, $V_{DS}$ = 0 V	_	—	±10	μA
Drain cut-off cu	rrent	I <sub>DSS</sub>	V <sub>DS</sub> = 60 V, V <sub>GS</sub> = 0 V	_	_	100	μA
Drain-source bi	reakdown voltage	V (BR) DSS	I <sub>D</sub> = 10 mA, V <sub>GS</sub> = 0 V	60	_	_	V
Gate threshold	voltage	V <sub>th</sub>	V <sub>DS</sub> = 10 V, I <sub>D</sub> = 1 mA	0.8	_	2.0	V
Drain-source ON resistance		R <sub>DS (ON)</sub>	V <sub>GS</sub> = 4 V, I <sub>D</sub> = 25 A	_	19	25	- mΩ
			V <sub>GS</sub> = 10 V, I <sub>D</sub> = 25 A	_	13	17	
Forward transfe	r admittance	Y <sub>fs</sub>	V <sub>DS</sub> = 10 V, I <sub>D</sub> = 25 A	28	40		S
Input capacitant	ce	C <sub>iss</sub>			3350		
Reverse transfer capacitance		C <sub>rss</sub>	V <sub>DS</sub> = 10 V, V <sub>GS</sub> = 0 V, f = 1 MHz		550		pF
Output capacitance		C <sub>oss</sub>		_	1600	_	
Switching time	Rise time	tr	$V_{GS} \stackrel{10V}{}_{0V} \int I_{D} = 25A$ $V_{OUT} \stackrel{V_{OUT}}{}_{RL} = 1.2\Omega$ $V_{DD} = 30V$ $Duty \leq 1\%, t_{w} = 10\mu s$	_	25	_	
	Turn-on time	t <sub>on</sub>		_	55	_	- ns
	Fall time	t <sub>f</sub>		_	60	_	
	Turn-off time	t <sub>off</sub>		_	180	_	
Total gate charge (Gate-source plus gate-drain)		Qg		_	110	_	
Gate-source charge		Q <sub>gs</sub>	V <sub>DD</sub> ≈ 48 V, V <sub>GS</sub> = 10 V, I <sub>D</sub> = 45 A		70	_	nC
Gate-drain ("miller") charge		Q <sub>gd</sub>			40	_	

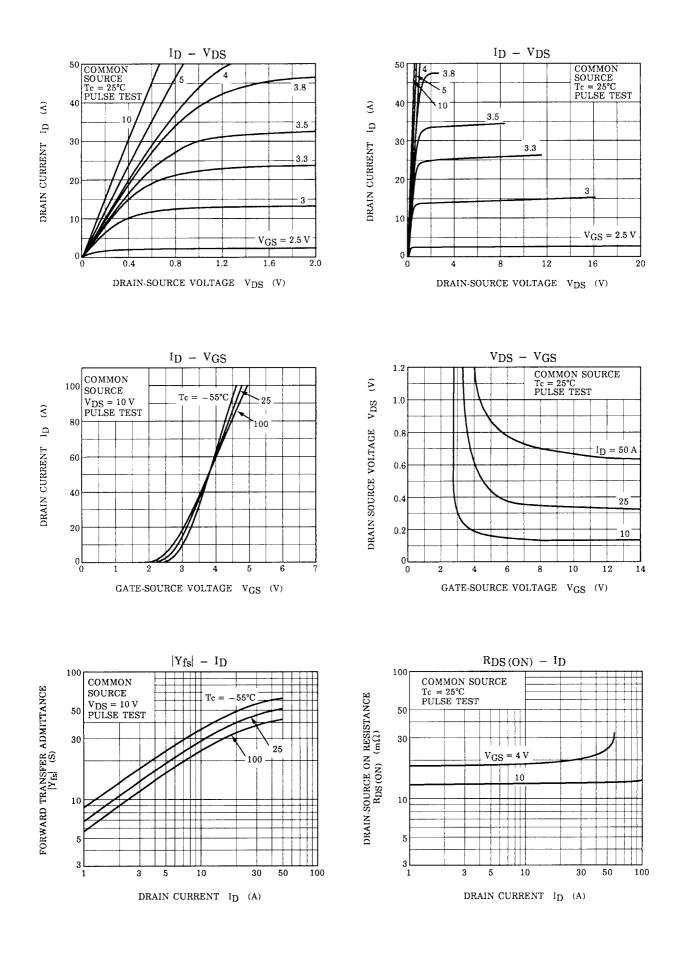
### Source–Drain Ratings and Characteristics (Ta = 25°C)

Characteristics	Symbol	Test Condition	Min	Тур.	Max	Unit
Continuous drain reverse current (Note 1)	I <sub>DR</sub>	—	_	_	45	А
Pulse drain reverse current (Note 1)	I <sub>DRP</sub>	_	_	_	180	А
Forward voltage (diode)	V <sub>DSF</sub>	I <sub>DR</sub> = 45 A, V <sub>GS</sub> = 0 V	_	_	-1.7	V
Reverse recovery time	t <sub>rr</sub>	I <sub>DR</sub> = 45 A, V <sub>GS</sub> = 0 V		120	—	ns
Reverse recovered charge	Q <sub>rr</sub>	dl <sub>DR</sub> / dt = 50 A / μs	_	0.2	_	μC

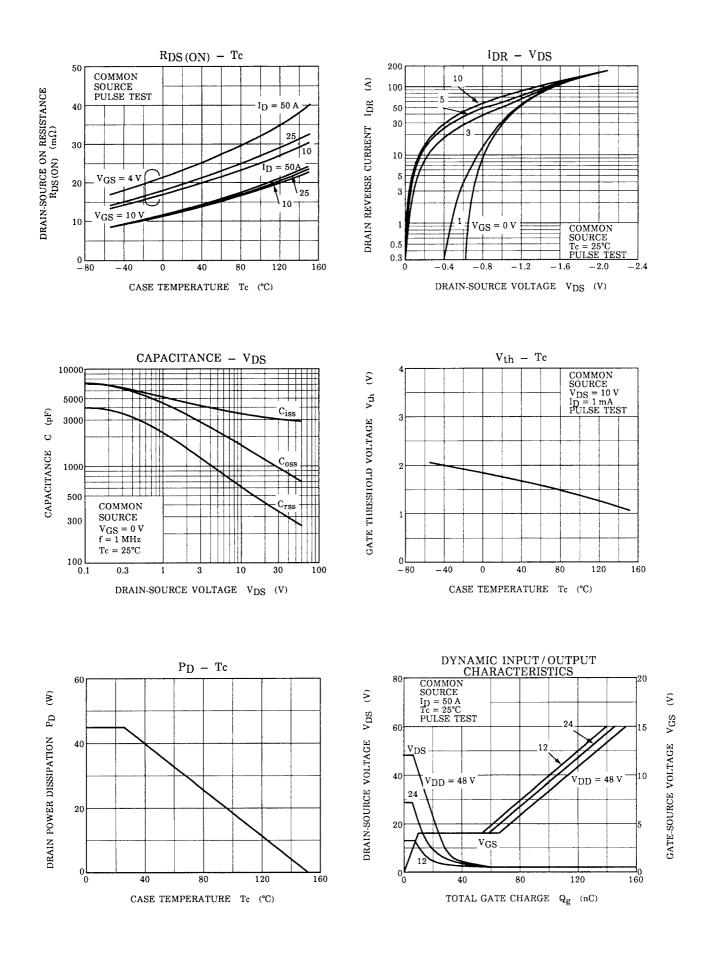
#### Marking

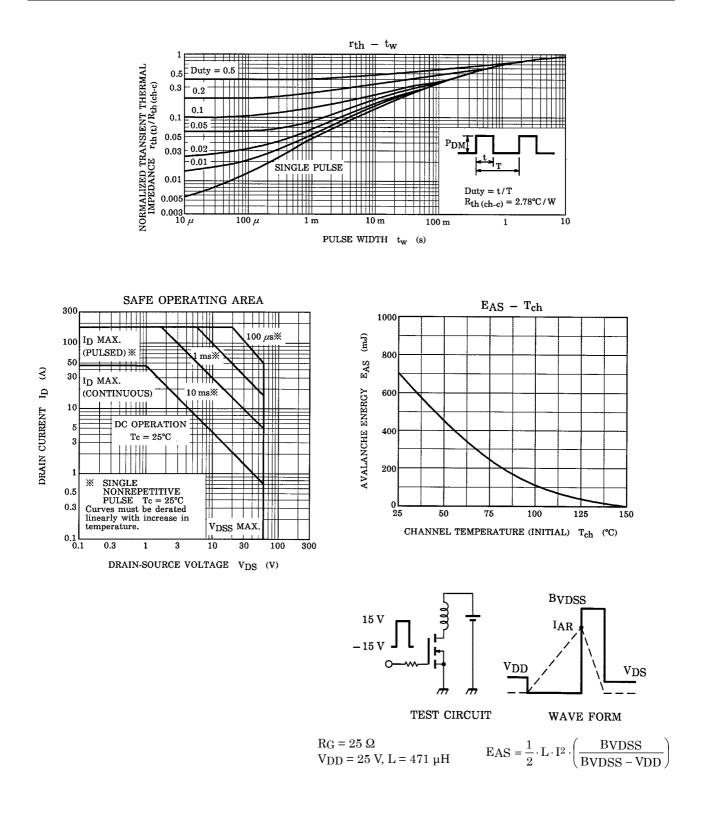


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